

Notice of References Cited	Application/Control No. 10/799,768	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Leslie J. Evanisko	Art Unit 2854	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,599,613	07-2003	Kasahara et al.	428/140
	B	US-6,573,877	06-2003	Wedel et al.	345/4
	C	US-5,601,928	02-1997	Katayama et al.	428/500
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 01/45957	06-2001	PCT	Fukushima et al.	---
	O	WO 98/36420	08-1998	PCT	Wedel et al.	---
	P	JP 2004-34642 A	02-2004	Japan	---	---
	Q	JP 2000-111660	04-2000	Japan	Osawa, Seiichi	---
	R	JP 11-326548	11-1998	Japan	---	---
	S	JP 2002-127389	05-2002	Japan	---	---
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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